Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10551039	FUJITA ET AL.
Examiner	Art Unit
NIKHII SRIRAMAN	3664

SEARCHED			
Class	Subclass	Date	Examiner
700	245, 248, 249, 250, 253	12/20/2008	NS

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Marc McDieunel	12/20/2008	
Assignee search on East, Inventor search on eDan		
NPL, including IEEE databases searched (see attached history)		
Reviewed submitted IDS references	7/12/2009	
Updated search in light of claim amendments; consulted with Examiner Jorge Peche and Examiner Kyung Kim on search strategy on claim interpretation	12/19/2009	
Consulted with Examiner Lin Olsen on apparatus claim construction in light of removal of "means plus function" language in Applicant's amendment	6/25/2010	

	INTERFERENCE SEA	RCH	
Class	Subclass	Date	Examine

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